

Search Notes

Application/Control No.

10/780,932

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

CHEN, KUN-HONG

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E51.005, E33.064, E31.126 & 79	7/20/2006	C.C.
257	E29.151	7/20/2006	C.C.
257	E23.157	7/20/2006	C.C.
257	758 & 449	7/20/2006	C.C.
257	749 & 347	7/20/2006	C.C.
257	350 & 43	7/20/2006	C.C.
438	609	7/20/2006	C.C.
174	255 - 258	7/20/2006	C.C.
349	139 & 149	7/20/2006	C.C.
349	152	7/20/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
As same	as above	7/20/2006	C.C.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	7/20/2006	C.C.
Consulted with Sheila Clark 257/43, 449, 758 TFT array and ITO	4/1/2005	C.C.
Consulted with John Vigushin 174/255 - 258	4/1/2005	C.C.
Consulted with George Fourson 257/79, 347, 350, 749, E33.064 and E23.157 438/609	4/1/2006	C.C.
Consulted with David Graybill 257/449, 749, 758, E51.005, E33.064, E31.126 and E29.151	4/1/2006	C.C.
Consulted with George Eckert 349/139, 149 and 152	4/1/2005	C.C.